

**AMENDMENTS TO THE CLAIMS:**

Kindly cancel claim 5, without prejudice.

This listing of claims will replace all prior versions and listings of claims in the Application:

**Claim 1 (previously presented).** A measuring instrument for noncontact measurement of conductivity of a silicon wafer using a microwave, the measuring instrument comprising:

an oscillator operating at a frequency not more than 100 GHz for oscillating the microwave;

a circulator connected to the oscillator;

a horn antenna connected to the circulator, the horn antenna transmitting the microwave to an upper surface of the silicon wafer and receiving a reflected wave from the upper surface of the silicon wafer;

a detector connected to said circulator, the detector outputting a voltage proportional to a square of magnitude of the wave from the upper surface of said silicon wafer; and

a computer for computing conductivity of said silicon wafer from said voltage.

**Claim 2 (previously presented).** A measuring instrument according to claim 1, wherein said circulator is connected to the oscillator through an isolator.

**Claim 3 (previously presented).** A measuring instrument according to claim 1, wherein a frequency of the microwave oscillating in said oscillator is 94 GHz.

**Claim 4 (previously presented).** A measuring instrument according to claim 2, wherein a frequency of the microwave oscillating in said oscillator is 94 GHz.

**Claim 5 (cancelled).**